PLS155

DESCRIPTION

The PLS155 is a 3-State output, registered logic element combining AND/OR gate arrays with clocked J-K flip-flops. These J-K flip-flops are dynamically convertible to D-type via a "fold-back" inverting buffer and control gate F_C. It features 4 registered I/O outputs (F) in conjunction with 8 bidirectional I/O lines (B). These yield variable I/O gate and register configurations via control gates (D, L) ranging from 16 inputs to 12 outputs.

The AND/OR arrays consist of 32 logic AND gates, 13 control AND gates, and 21 OR gates with fusible link connections for programming I/O polarity and direction. All AND gates are linked to 4 inputs (I), bidirectional I/O lines (B), internal flip-flop outputs (Q), and Complement Array output (C). The Complement Array consists of a NOR gate optionally linked to all AND gates for generating and propagating complementary AND terms.

On-chip T/C buffers couple either True (I, B, Q) or Complement (I, B, Q, C) input polarities to all AND gates, whose outputs can be optionally linked to all OR gates. Any of the 32 AND gates can drive bidirectional I/O lines (B), whose output polarity is individually programmable through a set of Ex-OR gates for implementing AND-OR or AND-NOR logic functions. Similarly, any of the AND gates can drive the J-K inputs of all flip-flops. The Asynchronous Preset and Reset lines (P, R), are driven from the OR matrix.

All flip-flops are positive edge-triggered and can be used as input, output or I/O (for interfacing with a bidirectional data bus) in conjunction with load control gates (L), steering inputs (I), (B), (Q) and programmable output select lines (E).

The PLS155 is field programmable, enabling the user to quickly generate custom patterns using standard programming equipment.

Order codes are listed below.

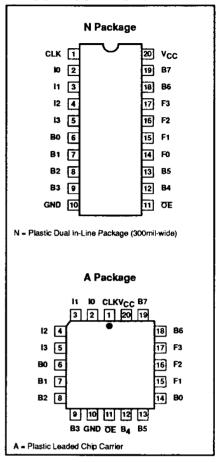
FEATURES

- f_{MAX} = 14MHz
 - 18.2MHz clock rate
- Field-Programmable (Ni-Cr link)
- 4 dedicated inputs
- 13 control gates
- 32 AND gates
- 21 OR gates
- 45 product terms:
- 32 logic terms
- 13 control terms
- 8 bidirectional I/O lines
- 4 bidirectional registers
- J-K, T, or D-type flip-flops
- Asynchronous Preset/Reset
- Complement Array
- Active-High or -Low outputs
- ◆ Programmable OE control
- Positive edge-triggered clock
- Input loading: –100µA (max.)
- Power dissipation: 750mW (typ.)
- TTL compatible
- 3-State outputs

APPLICATIONS

- Random sequential logic
- Synchronous up/down counters
- Shift registers
- Bidirectional data buffers
- Timing function generators
- System controllers/synchronizers
- Priority encoder/registers

PIN CONFIGURATIONS

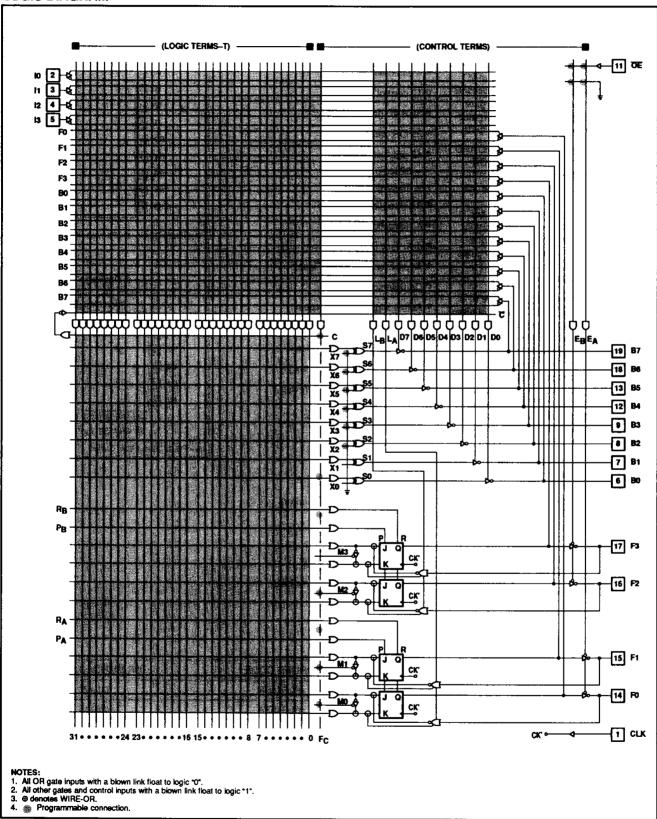


ORDERING INFORMATION

DESCRIPTION	ORDER CODE	DRAWING NUMBER		
20-Pin Plastic Dual In-Line Package (300mil-wide)	PLS155N	0408D		
20-Pin Plastic Leaded Chip Carrier	PLS155A	0400E		

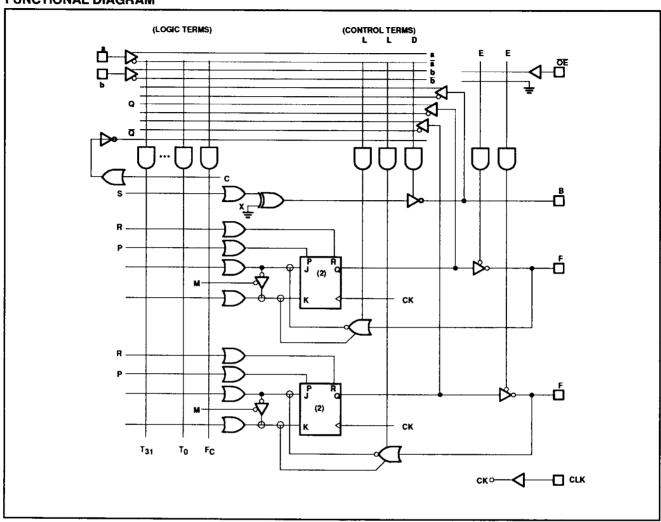
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LOGIC DIAGRAM



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FUNCTIONAL DIAGRAM



FLIP-FLOP TRUTH TABLE

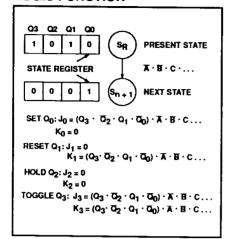
ŌE	L	СК	Р	R	J	Κ	Q	F	
Н								Hi-Z	
L	X	Х	Н	L	Х	Х	Н	L	
L	х	Х	L	Н	X	X	L	н	
L	L	1	L	L	L.	L	Q	۵	
L	L	1	L	L	L	Н	L	н	
L	L	1	L	L	Н	Ļ	Н	L	
L	L	1	L	L	Н	Н	ਹ	Q	
н	Н	1	L	Ļ	L	н	L	н•	
н	Н	1	L	L	Н	L	н	Ľ.	
+10V	Х	↑	Х	Х	L	Н	L	H**	
	х	1	Х	Х	Н	L	Н	L**	

- 1. Positive Logic: $J K = T_0 + T_1 + T_2 \dots T_{31}$ $T_n = \overline{C} \cdot (I_0 \cdot I_1 \cdot I_2 \dots) \cdot (Q_0 \cdot Q_1 \dots) \cdot (B_0 \cdot B_1 \cdot \dots)$ 2. $\uparrow \text{ denotes transition from Low to High level.}$

- 3. X = Don't care
 4. *= Forced at F_n pin for loading the J-K flip-flop in the Input mode. The load control term, Ln must be enabled (HIGH) and the p-terms that are connected to the associated flip-flop must be forced LOW
- (disabled) during Preload.
 At P = R = H, Q = H. The final state of Q depends on which is released first.
 * * = Forced at F_n pin to load J-K flip-flop independent of program code (Diagnostic mode). mode), 3-State B outputs.

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LOGIC FUNCTION



NOTE:

Similar logic functions are applicable for D and T mode flip-flops.

VIRGIN STATE

The factory shipped virgin device contains all fusible links intact, such that:

- 1. OE is always enabled.
- 2. Preset and Reset are always disabled.
- 3. All transition terms are disabled.
- All flip-flops are in D-mode unless otherwise programmed to J-K only or J-K or D (controlled).
- All B pins are inputs and all F pins are outputs unless otherwise programmed.

THERMAL RATINGS

TEMPERATURE				
Maximum junction	150°C			
Maximum ambient	75°C			
Allowable thermal rise ambient to junction	75°C			

ABSOLUTE MAXIMUM RATINGS¹

		RAT			
SYMBOL	PARAMETER	Min	Max	UNIT	
Vcc	Supply voltage		+7	V _{DC}	
V _{IN}	Input voltage		+5.5	V _{DC}	
Vout	Output voltage		+5.5	V _{DC}	
1 _{IN}	Input currents	-30	+30	mA	
l _{out}	Output currents		+100	mA	
T _{amb}	Operating temperature range	0	+75	°C	
T _{stg}	Storage temperature range	-65	+150	°C	

Stresses above those listed may cause malfunction or permanent damage to the device. This
is a stress rating only. Functional operation at these or any other condition above those
indicated in the operational and programming specification of the device is not implied.

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DC ELECTRICAL CHARACTERISTICS

 $0^{\circ}C \le T_{amb} \le +75^{\circ}C, 4.75V \le V_{CC} \le 5.25V$

				LIMITS		
SYMBOL	PARAMETER	TEST CONDITION	MIN	TYP1	MAX	UNIT
Input volta	age ²	•		•	•	
V _{IH}	High	V _{CC} = MAX	2.0			٧
V_{IL}	Low	V _{CC} = MIN			0.8	٧
Vic	Clamp	V _{CC} = MIN, I _{IN} = -12mA		-0.8	-1.2	٧
Output vo	ltage ²					
		V _{CC} = MIN				
V _{OH}	High	I _{OH} = -2mA	2.4			٧
V _{OL}	Low	i _{OL} = 10mA		0.35	0.5	٧
Input curr	ent ⁵					
		V _{CC} = MAX				
I _{IH}	High	V _{IN} = 5.5V	Ì	<1	80	μΑ
I _{IL}	Low	V _{IN} = 0.45V		-10	-100	μΑ
Output cu	rrent					
		V _{CC} = MAX				
I _{O(OFF)}	Hi-Z state ^{5, 6}	V _{OUT} = 5.5V		1	80	μΑ
		V _{OUT} = 0.45V		-1	-140	μΑ
los	Short circuit ^{3, 7}	V _{OUT} = 0V	-15		-70	mA
lcc	V _{CC} supply current ⁴	V _{CC} = MAX		150	190	mA
Capacitan	се		•		-	
		V _{CC} = 5.0V				
CiN	Input	V _{IN} = 2.0V		8		ρF
Cout	Output	V _{OUT} = 2.0V		15		pF

- All typical values are at V_{CC} = 5V, T_{amb} = +25°C.
 All voltage values are with respect to network ground terminal.
 Test one at a time.
- lest one at a time.
 l_{CC} is measured with the OE input grounded, all other inputs at 4.5V and the outputs open.
 Leakage values are a combination of input and output leakage.
 Measured with V_{IH} applied to OE.
 Duration of short circuit should not exceed 1 second.

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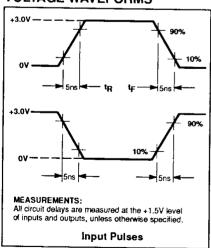
AC ELECTRICAL CHARACTERISTICS

 $0^{\circ}\text{C} \le \text{T}_{amb} \le +75^{\circ}\text{C}$, $4.75\text{V} \le \text{V}_{CC} \le 5.25\text{V}$, $\text{R}_1 = 470\Omega$, $\text{R}_2 = 1\text{k}\Omega$

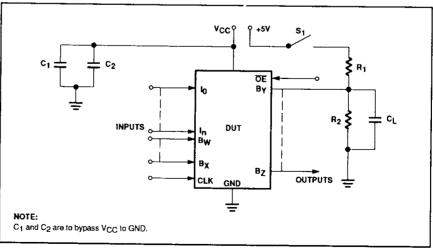
	PARAMETER		то		LIMITS			
SYMBOL		FROM		TEST CONDITION	MIN	TYP1	MAX	UNIT
Pulse wid	lth						1	
tскн	Clock ² High	CK+	CK-	C _L = 30pF	25	20		ns
t _{CKL}	Clock Low	CK-	CK+	C _L = 30pF	30	20		ns
t _{CKP}	Period	CK+	CK+	C _L = 30pF	70	50		ns
t _{PRH}	Preset/Reset pulse	(I,B) –	(I,B) +	C _L = 30pF	40	30		ns
Setup tim	e ⁵		<u></u>				1	1
t _{iS1}	Input	(I,B) ±	CK+	C ₁ = 30pF	40	30	Ī	ns
t _{IS2}	Input (through F _n)	F±	CK+	C _L = 30pF	20	10		ns
t _{IS3}	Input (through Complement Array) ⁴	(I,B) ±	CK+	C _L = 30pF	65	40		ns
Hold time				- 		<u> </u>		<u></u>
t _{iH1}	Input	(I,P) ±	CK+	C ₁ = 30pF	0	-10		ns
t _{IH2}	Input	F±	CK+	C _L = 30pF	15	10		ns
Propagati	on delays			<u> </u>		l		
tско	Clock	CK+	F±	C _L = 30pF		25	30	ns
t _{OE1}	Output enable ³	OE –	F-	C _L = 30pF		20	30	ns
t _{OD1}	Output disable ³	OE +	F+	C _L = 5pF		20	30	ns
t _{PD}	Output	(I,B) ±	В±	C _L = 30pF		40	50	ns
t _{OE2}	Output enable ³	(I,B) +	В±	C _L = 30pF		35	55	ns
t _{OD2}	Output disable ³	(I,B) –	B +	C _L = 5pF		30	35	ns
t _{PRO}	Preset/Reset	(I,B) +	F±	C _L = 30pF		50	55	ns

- All typical values are at V_{CC} = 5V, T_{amb} = +25°C.
 To prevent spurious clocking, clock rise time (10% 90%) ≤ 10ns.
- 3. For 3-State output; output enable times are tested with C_L = 30pF to the 1.5V level, and S₁ is open for high-impedance to High tests and closed for high-impedance to Low tests. Output disable times are tested with C_L = 5pF. High-to-High impedance tests are made to an output voltage of $V_T = (V_{OH} - 0.5V)$ with S_1 open, and Low-to-High impedance tests are made to the $V_T = (V_{OL} + 0.5V)$ level with S_1 closed.
- When using the Complement Array t_{CKP} = 95ns (min).
- Limits are guaranteed with 12 product terms maximum connected to each sum term line.
- For test circuits, waveforms and timing diagrams see the following pages.

VOLTAGE WAVEFORMS

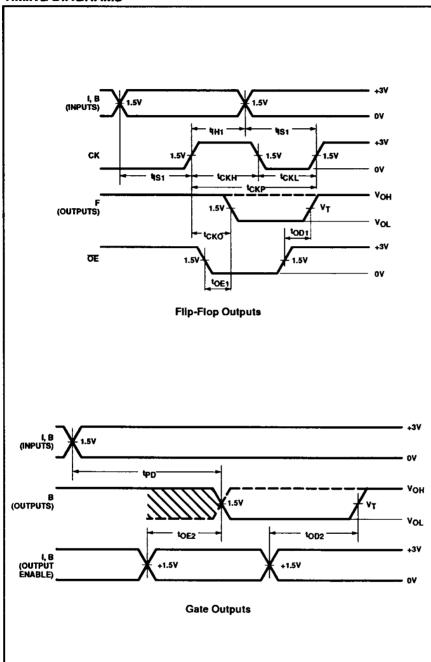


TEST LOAD CIRCUIT



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TIMING DIAGRAMS

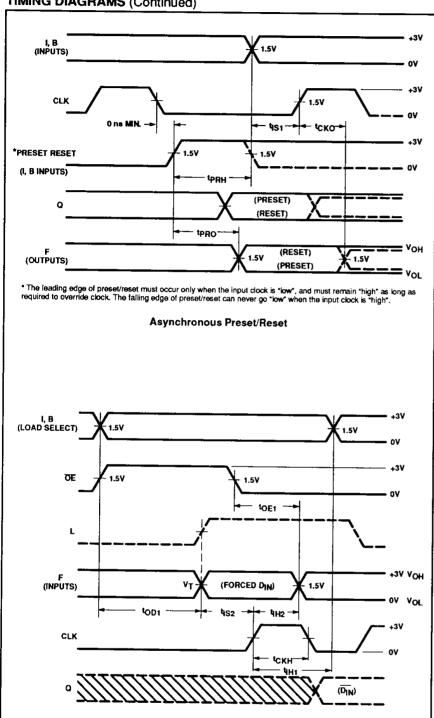


TIMING DEFINITIONS

TIMING DEFINITIONS					
SYMBOL	PARAMETER				
t скн	Width of input clock pulse.				
t _{CKL}	Interval between clock pulses.				
t _{CKP}	Clock period.				
t PRH	Width of preset input pulse.				
t _{IS1}	Required delay between beginning of valid input and positive transition of clock.				
t _{IS2}	Required delay between beginning of valid input forced at flip-flop output pins, and positive transition of clock.				
t _{iH1}	Required delay between positive transition of clock and end of valid input data.				
t _{IH2}	Required delay between positive transition of clock and end of valid input data forced at flip-flop output pins.				
^t cko	Delay between positive transition of clock and when outputs become valid (with OE Low).				
t _{OE1}	Delay between beginning of Output Enable Low and when outputs become valid.				
top1	Delay between beginning of Output Enable High and when outputs are in the OFF-State.				
t PD	Propagation delay between combinational inputs and outputs.				
t _{OE2}	Delay between predefined Output Enable High, and when combinational outputs become valid.				
t _{OD2}	Delay between predefined Output Enable Low and when combinational outputs are in the OFF-State.				
ФЯО	Delay between positive transition of predefined Preset/Reset input, and when flip-flop outputs become valid.				

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Flip-Flop Input Mode

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LOGIC PROGRAMMING

The PLS155 is fully supported by industry standard (JEDEC compatible) PLD CAD tools, including Philips' Semiconductors SNAP, Data I/O Corporation's ABEL™ and Logical Devices Inc.'s CUPL™ design software packages.

All packages allow Boolean and state equation entry formats. SNAP, ABEL and CUPL also accept, as input, schematic capture format.

PLS155 logic designs can also be generated using the program table entry format detailed on the following pages. This program table entry format is supported by the Philips Semiconductors SNAP PLD design software package only.

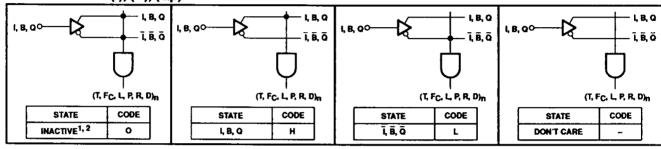
To implement the desired logic functions, the state of each logic variable from logic equations (I, B, O, P, etc.) is assigned a symbol. The symbols for TRUE,

COMPLEMENT, INACTIVE, PRESET, etc., are defined below.

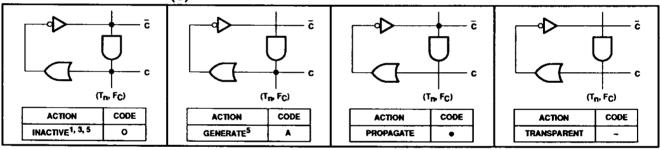
PROGRAMMING AND SOFTWARE SUPPORT

Refer to Section 9 (Development Software) and Section 10 (Third-party Programmer/ Software Support) of this data handbook for additional information.

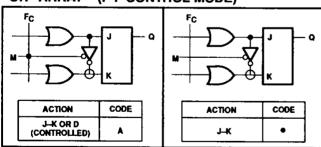
"AND" ARRAY - (I), (B), (Qp)



"COMPLEMENT" ARRAY - (C)

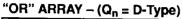


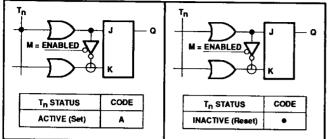
"OR" ARRAY - (F-F CONTROL MODE)



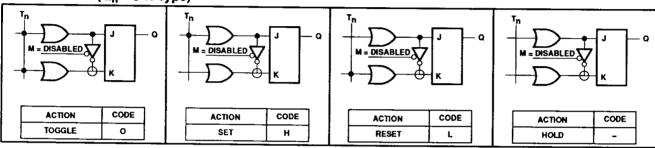
Notes on following page.

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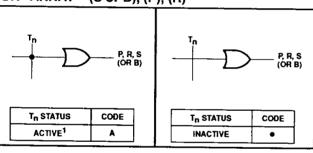




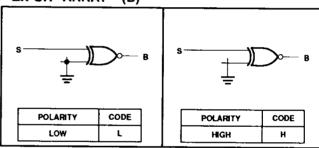
"OR" ARRAY – $(Q_n = J-K Type)$



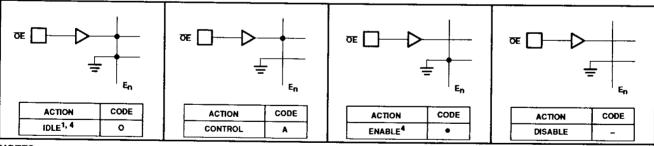
"OR" ARRAY - (S or B), (P), (R)





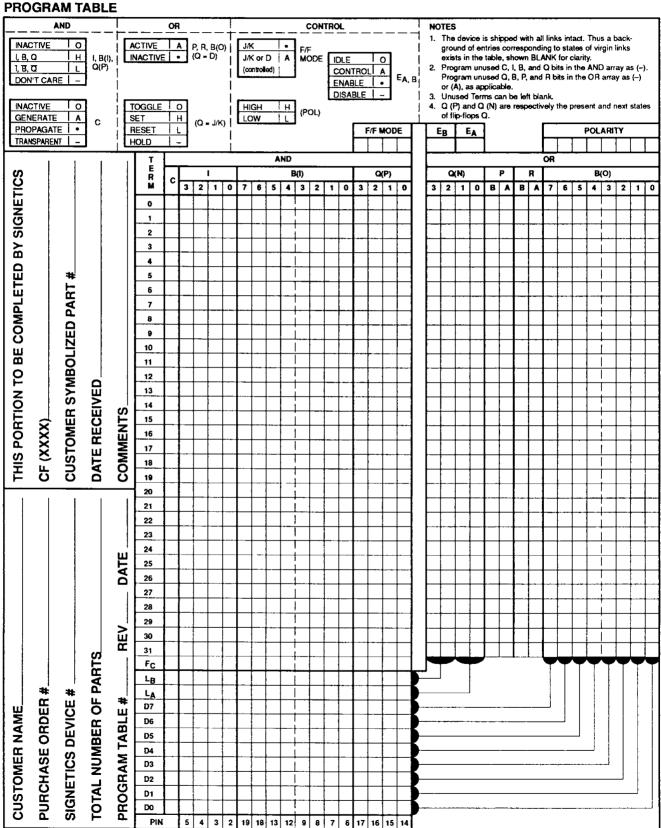


"OE" ARRAY - (E)



- 1. This is the initial unprogrammed state of all link pairs. It is normally associated with all unused (inactive) AND gates.
- Any gate (T, F_C, L, P, R, D)_n will be unconditionally inhibited if both of the I, B, or Q links are left intact. To prevent oscillations, this state is not allowed for C link pairs coupled to active gates T_n, F_C.
- $E_n = O$ and $E_n = \bullet$ are logically equivalent states, since both cause F_n outputs to be unconditionally enabled.
- These states are not allowed for control gates (L, P, R, D)_n due to their lack of "OR" array links.

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SNAP RESOURCE SUMMARY DESIGNATIONS

